

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/812,467 | Applicant(s)/Patent Under Reexamination NAIK ET AL. | |
| | Examiner Tu M. Nguyen | Art Unit 3748 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| * | A | US-5,775,099 | 07-1998 | Ito et al. | 60/274 |
| * | B | US-2002/0029562 | 03-2002 | Ishii et al. | 60/277 |
| * | C | US-6,763,657 | 07-2004 | Wachi et al. | 60/285 |
| * | D | US-6,722,121 | 04-2004 | Gui et al. | 60/285 |
| * | E | US-5,732,554 | 03-1998 | Sasaki et al. | 60/278 |
| * | F | US-6,336,320 | 01-2002 | Tanaka et al. | 60/285 |
| * | G | US-6,434,929 | 08-2002 | Nishimura et al. | 60/278 |
| * | H | US-6,553,757 | 04-2003 | Surnilla et al. | 60/285 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.